4-output 1.8V PCIe Gen1-2-3 Zero-delay/Fanout Buffer (ZDB/FOB)

DATASHEET

Description

The 9DBV0431 is a member of IDT's SOC-Friendly 1.8V Very-Low-Power (VLP) PCIe family. It can also be used for 50M or 125M Ethernet Applications via software frequency selection. The device has 4 output enables for clock management, and 3 selectable SMBus addresses.

Recommended Application

1.8V PCIe Gen1-2-3 Zero-Delay/Fan-out Buffer (ZDB/FOB)

Output Features

• 4 - 1-200Hz Low-Power (LP) HCSL DIF pairs w/Zo=100ohms

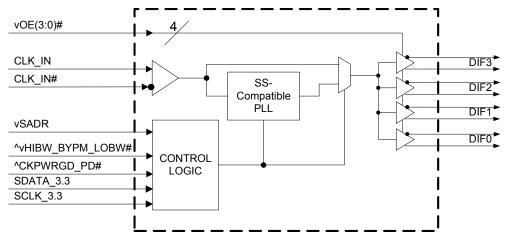
Key Specifications

- DIF cycle-to-cycle jitter <50ps
- DIF output-to-output skew <50ps
- DIF additive phase jitter is <100fs rms for PCle Gen3
- DIF additive phase jitter <300fs rms for 12k-20MHz

Features/Benefits

- LP-HCSL outputs save 8 resistors; minimal board space and BOM cost
- 53mW typical power consumption in PLL mode; minimal power consumption
- OE# pins; support DIF power management
- HCSL compatible differential input; can be driven by common clock sources
- Programmable Slew rate for each output; allows tuning for various line lengths
- Programmable output amplitude; allows tuning for various application environments
- Pin/software selectable PLL bandwidth and PLL Bypass; minimize phase jitter for each application
- Outputs blocked until PLL is locked; clean system start-up
- Software selectable 50MHz or 125MHz PLL operation; useful for Ethernet applications
- Configuration can be accomplished with strapping pins; SMBus interface not required for device control
- 3.3V tolerant SMBus interface works with legacy controllers
- Space saving 32-pin 5x5mm VFQFPN; minimal board space
- Selectable SMBus addresses; multiple devices can easily share an SMBus segment

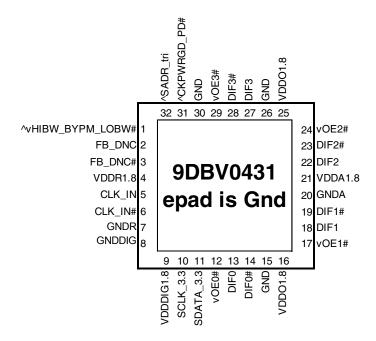
Block Diagram



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Pin Configuration



32-pin VFQFPN, 5x5 mm, 0.5mm pitch

^ prefix indicates internal 120KOhm pull up resistor ^v prefix indicates internal 120KOhm pull up AND pull down resistor (biased to VDD/2) v prefix indicates internal 120KOhm pull down resistor

SMBus Address Selection Table

	SADR	Address	+ Read/Write bit
State of SADR on first application of	0	1101011	X
CKPWRGD_PD#	M	1101100	X
	1	1101101	X

Power Management Table

CKPWRGD PD#	CLK IN	SMBus OEx bit OEx# Pin		DIF	PLL	
CKFWKGD_FD#	CLK_IN			True O/P	Comp. O/P	'
0	Х	Х	Х	Low	Low	Off
1	Running	0	Х	Low	Low	On ¹
1	Running	1	0	Running	Running	On ¹
1	Running	1	1	Low	Low	On ¹

^{1.} If Bypass mode is selected, the PLL will be off, and outputs will be running.

Power Connections

Pin Numb	oer	Decemention
VDD	GND	Description
4	7	Input receiver analog
9	8	Digital Power
16, 25	15,20,26,30	DIF outputs
21	20	PLL Analog

PLL Operating Mode

HiBW_BypM_LoBW#	MODE	Byte1 [7:6] Readback	Byte1 [4:3] Control
0	PLL Lo BW	00	00
M	Bypass	01	01
1	PLL Hi BW	11	11

Frequency Select Table

. ,		
FSEL	CLK_IN	DIFx
Byte3 [4:3]	(MHz)	(MHz)
00 (Default)	100.00	CLK_IN
01	50.00	CLK_IN
10	125.00	CLK_IN
11	Reserved	Reserved



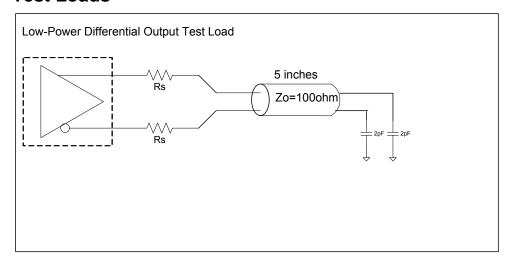
Pin Descriptions

Pin#	Pin Name	Туре	Pin Description
4	^vHIBW BYPM LOB	LATCHED	Trilevel input to select High BW, Bypass or Low BW mode.
1		IN	See PLL Operating Mode Table for Details.
	FB DNC	DNC	True clock of differential feedback. The feedback output and feedback input are
2	LP_DINC	DNC	connected internally on this pin. Do not connect anything to this pin.
_	ED DNC#	DNC	Complement clock of differential feedback. The feedback output and feedback
3	FB_DNC#	DINC	input are connected internally on this pin. Do not connect anything to this pin.
4	VDDR1.8	PWR	1.8V power for differential input clock (receiver). This VDD should be treated as an
4	VDDN1.0	FVVN	Analog power rail and filtered appropriately.
5	CLK_IN	IN	True Input for differential reference clock.
6	CLK_IN#	IN	Complementary Input for differential reference clock.
7	GNDR	GND	Analog Ground pin for the differential input (receiver)
8	GNDDIG	GND	Ground pin for digital circuitry
9	VDDDIG1.8	PWR	1.8V digital power (dirty power)
10	SCLK_3.3	IN	Clock pin of SMBus circuitry, 3.3V tolerant.
11	SDATA_3.3	I/O	Data pin for SMBus circuitry, 3.3V tolerant.
10	VOE0#	INI	Active low input for enabling DIF pair 0. This pin has an internal pull-down.
12	vOE0#	IN	1 =disable outputs, 0 = enable outputs
13	DIF0	OUT	Differential true clock output
14	DIF0#	OUT	Differential Complementary clock output
15	GND	GND	Ground pin.
16	VDDO1.8	PWR	Power supply for outputs, nominally 1.8V.
17	VOE1#	IN	Active low input for enabling DIF pair 1. This pin has an internal pull-down.
17	vOE1#	IIN	1 =disable outputs, 0 = enable outputs
18	DIF1	OUT	Differential true clock output
19	DIF1#	OUT	Differential Complementary clock output
20	GNDA	GND	Ground pin for the PLL core.
21	VDDA1.8	PWR	1.8V power for the PLL core.
22	DIF2	OUT	Differential true clock output
23	DIF2#	OUT	Differential Complementary clock output
24	VOE2#	IN	Active low input for enabling DIF pair 2. This pin has an internal pull-down.
24	vOE2#	IIN	1 =disable outputs, 0 = enable outputs
25	VDDO1.8	PWR	Power supply for outputs, nominally 1.8V.
26	GND	GND	Ground pin.
27	DIF3	OUT	Differential true clock output
28	DIF3#	OUT	Differential Complementary clock output
20	vOE3#	IN	Active low input for enabling DIF pair 3. This pin has an internal pull-down.
29	VOES#	IIN	1 =disable outputs, 0 = enable outputs
30	GND	GND	Ground pin.
			Input notifies device to sample latched inputs and start up on first high assertion.
31	^CKPWRGD_PD#	IN	Low enters Power Down Mode, subsequent high assertions exit Power Down Mode.
			This pin has internal pull-up resistor.
32	ASADD tri	LATCHED	Tri-level latch to select SMBus Address. See SMBus Address Selection Table.
32	^SADR_tri	IN	Thriever ratch to select sividus Address. See Sividus Address Selection Table.
33	ePad	GND	Connect epad to ground.

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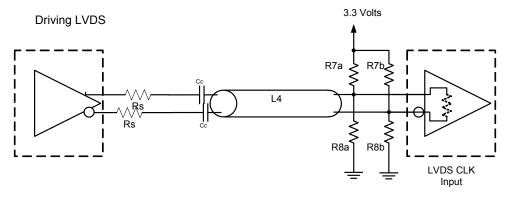
Test Loads



Alternate Differential Output Terminations

Rs	Zo	Units
33	100	Ohms
27	85	Oillis

Driving LVDS



Driving LVDS inputs with the 9DBV0431

	,		
	Receiver has Receiver does not		
Component	termination	have termination	Note
R7a, R7b	10K ohm	140 ohm	
R8a, R8b	5.6K ohm	75 ohm	
Cc	0.1 uF	0.1 uF	
Vcm	1.2 volts	1.2 volts	



Absolute Maximum Ratings

Stresses above the ratings listed below can cause permanent damage to the 9DBV0431. These ratings, which are standard values for IDT commercially rated parts, are stress ratings only. Functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods can affect product reliability. Electrical parameters are guaranteed only over the recommended operating temperature range.

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Power supply voltage	VDDxx	Applies to all VDD pins	-0.5		2.5	V	1,2
Input Voltage	V_{IN}		-0.5		$V_{DD} + 0.5V$	V	1, 3
Input High Voltage, SMBus	V_{IHSMB}	SMBus clock and data pins			3.6V	V	1
Storage Temperature	Ts		-65		150	°C	1
Junction Temperature	Tj				125	°C	1
Input ESD protection	ESD prot	Human Body Model	2000			V	1

¹Guaranteed by design and characterization, not 100% tested in production.

Electrical Characteristics-Clock Input Parameters

TA = T_{COM} or T_{IND}. Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

TA = 100M of 17ND; Supply Voltage per VBB of normal operation conditions, See Test Leads for Leading Conditions							
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Input High Voltage - DIF_IN	V _{IHDIF}	Differential inputs (single-ended measurement)	600	800	1150	mV	1
Input Low Voltage - DIF_IN	V_{ILDIF}	Differential inputs (single-ended measurement)	V _{SS} - 300	0	300	mV	1
Input Common Mode Voltage - DIF_IN	V_{COM}	Common Mode Input Voltage	300		725	mV	1
Input Amplitude - DIF_IN	V_{SWING}	Peak to Peak value (VIHDIF - VILDIF), single-ended	300		1450	mV	1
Input Slew Rate - DIF_IN	dv/dt	Measured differentially	0.4			V/ns	1,2
Input Leakage Current	I _{IN}	$V_{IN} = V_{DD}$, $V_{IN} = GND$	-5		5	uA	1
Input Duty Cycle	d_{tin}	Measurement from differential wavefrom	45	•	55	%	1
Input Jitter - Cycle to Cycle	J_{DIFIn}	Differential Measurement	0		150	ps	1

¹ Guaranteed by design and characterization, not 100% tested in production.

² Operation under these conditions is neither implied nor guaranteed.

³ Not to exceed 2.5V.

² Slew rate measured through +/-75mV window centered around differential zero



Electrical Characteristics-Input/Supply/Common Parameters-Normal Operating Conditions

TA = T_{COM} or T_{IND}. Supply Voltage per VDD of normal operation conditions. See Test Loads for Loading Conditions

THE TOM OF TIND; Cupping to	itage per VD	of normal operation conditions, See Test Loads for	Loading Con	uitions			
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
1.8V Supply Voltage	VDD	Supply voltage for core, analog and LVCMOS outputs	1.7	1.8	1.9	V	1
Ambient Operating	T _{COM}	Commmercial range	0	25	70	°C	1
Temperature	T_IND	Industrial range	-40	25	85		1
Input High Voltage	V_{IH}	Single-ended inputs, except SMBus	0.75 V _{DD}		$V_{DD} + 0.3$	V	1
Input Mid Voltage	V_{IM}	Single-ended tri-level inputs ('_tri' suffix)	$0.4~V_{DD}$		0.6 V _{DD}	٧	1
Input Low Voltage	V_{IL}	Single-ended inputs, except SMBus	-0.3		0.25 V _{DD}	V	1
	I _{IN}	Single-ended inputs, $V_{IN} = GND$, $V_{IN} = VDD$	-5		5	uA	1
Input Current	I _{INP}	Single-ended inputs $V_{IN} = 0 \text{ V}$; Inputs with internal pull-up resistors $V_{IN} = \text{VDD}$; Inputs with internal pull-down resistors	-200		200	uA	1
	F_{ibyp}	Bypass mode	1		200	MHz	2
Input Frequency	F _{ipII100}	100MHz PLL mode	50	100	140	MHz	2
input i requency	F _{ipll125}	125MHz PLL mode	62.5	125	175	MHz	2
	F _{ipll62}	50MHz PLL mode	25	50	65	MHz	2
Pin Inductance	L_{pin}				7	nΗ	1
	C_{IN}	Logic Inputs, except DIF_IN	1.5		5	рF	1
Capacitance	C _{INDIF_IN}	DIF_IN differential clock inputs	1.5		2.7	рF	1,6
	C _{OUT}	Output pin capacitance			6	0 °C	1
Clk Stabilization	T _{STAB}	From V _{DD} Power-Up and after input clock stabilization or de-assertion of PD# to 1st clock		0.6	1	ms	1,2
Input SS Modulation Frequency	f _{MODIN}	Allowable Frequency (Triangular Modulation)	30	31.5	33	kHz	1
OE# Latency	t _{LATOE#}	DIF start after OE# assertion DIF stop after OE# deassertion	1		3	clocks	1,3
Tdrive_PD#	t _{DRVPD}	DIF output enable after PD# de-assertion		175	300	us	1,3
Tfall	t _F	Fall time of single-ended control inputs			5	ns	1,2
Trise	t_R	Rise time of single-ended control inputs			5	ns	1,2
SMBus Input Low Voltage	V_{ILSMB}	$V_{DDSMB} = 3.3V$, see note 4 for $V_{DDSMB} < 3.3V$			0.8	٧	1,4
SMBus Input High Voltage	V_{IHSMB}	$V_{DDSMB} = 3.3V$, see note 5 for $V_{DDSMB} < 3.3V$	2.1		3.6	٧	1,5
SMBus Output Low Voltage	V_{OLSMB}	@ I _{PULLUP}			0.4	V	1
SMBus Sink Current	I _{PULLUP}	@ V _{OL}	4			mA	1
Nominal Bus Voltage	$V_{\rm DDSMB}$		1.7		3.6	V	1
SCLK/SDATA Rise Time	t _{RSMB}	(Max VIL - 0.15) to (Min VIH + 0.15)			1000	ns	1
SCLK/SDATA Fall Time	t _{FSMB}	(Min VIH + 0.15) to (Max VIL - 0.15)			300	ns	1
SMBus Operating Frequency	f _{MAXSMB}	Maximum SMBus operating frequency			400	kHz	1,7

¹Guaranteed by design and characterization, not 100% tested in production.

²Control input must be monotonic from 20% to 80% of input swing.

³Time from deassertion until outputs are >200 mV

 $^{^4}$ For $V_{\text{DDSMB}} < 3.3 V, \ V_{\text{ILSMB}} <= 0.25 V_{\text{DDSMB}}$

 $^{^{5}}$ For $V_{\text{DDSMB}} < 3.3 V, \ V_{\text{IHSMB}} >= 0.7 V_{\text{DDSMB}}$

⁶DIF_IN input

⁷The differential input clock must be running for the SMBus to be active



Electrical Characteristics-DIF 0.7V Low Power HCSL Outputs

TA = T_{COM} or T_{IND}: Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

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PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Slew rate	Trf	Scope averaging on 3.0V/ns setting	2	3.2	4	V/ns	1, 2, 3
Siew rate	111	Scope averaging on 2.0V/ns setting	1.3	2.3	3.3	V/ns	1, 2, 3
Slew rate matching	ΔTrf	Slew rate matching, Scope averaging on		5.4	20	%	1, 2, 4
Voltage High	V _{HIGH}	Statistical measurement on single-ended signal using oscilloscope math function. (Scope	660	779	850	mV	1,7
Voltage Low	V_{LOW}	averaging on)	-150	21	150	1110	1,7
Max Voltage	Vmax	Measurement on single ended signal using		835	1150	mV	1
Min Voltage	Vmin	absolute value. (Scope averaging off)	-300	-42		1117	1
Vswing	Vswing	Scope averaging off	300	1515		mV	1,2,7
Crossing Voltage (abs)	Vcross_abs	Scope averaging off	250	409	550	mV	1,5,7
Crossing Voltage (var)	Δ-Vcross	Scope averaging off		14	140	mV	1, 6

¹Guaranteed by design and characterization, not 100% tested in production. $C_L = 2pF$ with $R_S = 33Ω$ for Zo = 50Ω (100Ω differential trace impedance).

Electrical Characteristics-Current Consumption

TA = T_{COM} or T_{IND}; Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Operating Supply Current	I _{DDROP}	VDDR, @100MHz		4.2	6	mA	1
(PLL Mode)	I _{DDOP}	VDDA + VDD1.8, @100MHz		27	33	mA	1
Operating Supply Current	I _{DDROP}	VDDR, @100MHz		2.2	3	mA	1
(PLL-Bypass Mode)	Note		20	25	mA	1	
Powordown Current	I _{DDRPD}	VDDR, CKPWRGD_PD# = 0		0.014	0.3		1,2
Powerdown Current	I _{DDPD}	VDDA + VDD1.8, CKPWRGD_PD# = 0		0.95	1.2	mA	1, 2

¹ Guaranteed by design and characterization, not 100% tested in production.

² Measured from differential waveform

³ Slew rate is measured through the Vswing voltage range centered around differential 0V. This results in a +/-150mV window around differential 0V.

⁴ Matching applies to rising edge rate for Clock and falling edge rate for Clock#. It is measured using a +/-75mV window centered on the average cross point where Clock rising meets Clock# falling. The median cross point is used to calculate the voltage thresholds the oscilloscope is to use for the edge rate calculations.

⁵ Vcross is defined as voltage where Clock = Clock# measured on a component test board and only applies to the differential rising edge (i.e. Clock rising and Clock# falling).

⁶ The total variation of all Vcross measurements in any particular system. Note that this is a subset of Vcross_min/max (Vcross absolute) allowed. The intent is to limit Vcross induced modulation by setting Δ -Vcross to be smaller than Vcross absolute.

⁷ At default SMBus settings.

² Input clock stopped, and CKPWRGD_PD# pin low.



Electrical Characteristics-Output Duty Cycle, Jitter, Skew and PLL Characteristics

TA = T_{COM} or T_{IND}: Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

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PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
PLL Bandwidth	BW	-3dB point in High BW Mode	2	2.7	4	MHz	1,5
FLL Balldwidth	DVV	-3dB point in Low BW Mode	1	1.4	2	MHz	1,5
PLL Jitter Peaking	t _{JPEAK}	Peak Pass band Gain		1.2	2	dB	1
Duty Cycle	t _{DC}	Measured differentially, PLL Mode	45	50.1	55	%	1
Duty Cycle Distortion	t _{DCD}	Measured differentially, Bypass Mode @100MHz	-1	-0.1	1	%	1,3
Skew, Input to Output	t _{pdBYP}	Bypass Mode, V _T = 50%	2550	3370	4200	% 1	1
Skew, Input to Output	t _{pdPLL}	PLL Mode V _T = 50%	0	112	200	ps	1,4
Skow Output to Output	+	Commercial Operating Range, V _T = 50%		33	50	ps	1,4
Skew, Output to Output	t _{sk3}	Industrial Operating Range, V _T = 50%		33	55	ps	1,4
Jitter, Cycle to cycle	+.	PLL mode		13	50	ps	1,2
Jitter, Cycle to Cycle	t _{jcyc-cyc}	Additive Jitter in Bypass Mode		0.1	1	ps	1,2

¹ Guaranteed by design and characterization, not 100% tested in production.

Electrical Characteristics-Phase Jitter Parameters

TA = T_{COM} or T_{IND}. Supply Voltage per VDD of normal operation conditions, See Test Loads for Loading Conditions

						INDUSTRY		
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	LIMIT	UNITS	Notes
	t _{iphPCleG1}	PCIe Gen 1		32	52	86	ps (p-p)	1,2,3
PARAMETER Phase Jitter, PLL Mode Additive Phase Jitter, Bypass Mode		PCIe Gen 2 Lo Band 10kHz < f < 1.5MHz		0.8	1.4	3	ps (rms)	1,2
	t _{jphPCleG2}	PCIe Gen 2 High Band 1.5MHz < f < Nyquist (50MHz)		2.4	2.6	3.1	ps (rms)	1,2
	t _{jphPCleG3}	PCIe Gen 3 (PLL BW of 2-4MHz, CDR = 10MHz)		0.5	0.6	1	ps (rms)	1,2,4
	t _{jphSGMII}	125MHz, 1.5MHz to 10MHz, -20dB/decade rollover < 1.5MHz, -40db/decade rolloff > 10MHz		1.9	2.2	3	ps (rms)	1,6
	t _{jphPCleG1}	PCIe Gen 1		0.1	5.0	N/A	ps (p-p)	1,2,3
		PCIe Gen 2 Lo Band 10kHz < f < 1.5MHz		0.2	0.3	N/A	ps (rms)	1,2,4
	t _{jphPCleG2}	PCIe Gen 2 High Band 1.5MHz < f < Nyquist (50MHz)		0.05	0.1	N/A	ps (rms)	1,2,4
	t _{jphPCleG3}	PCIe Gen 3 (PLL BW of 2-4MHz, CDR = 10MHz)		0.05	0.1	N/A	ps (rms)	1,2,4
2,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	t _{jphSGMIIM0}	125MHz, 1.5MHz to 10MHz, -20dB/decade rollover < 1.5MHz, -40db/decade rolloff > 10MHz		165	200	N/A	fs (rms)	1,6
	t _{jphSGMIIM1}	125MHz, 12kHz to 20MHz, -20dB/decade rollover < 1.5MHz, -40db/decade rolloff > 10MHz		251	300	N/A	fs (rms)	1,6

¹Guaranteed by design and characterization, not 100% tested in production.

² Measured from differential waveform

³ Duty cycle distortion is the difference in duty cycle between the output and the input clock when the device is operated in bypass mode.

⁴ All outputs at default slew rate

⁵ The MIN/TYP/MAX values of each BW setting track each other, i.e., Low BW MAX will never occur with Hi BW MIN.

² See http://www.pcisig.com for complete specs

³ Sample size of at least 100K cycles. This figures extrapolates to 108ps pk-pk @ 1M cycles for a BER of 1-12.

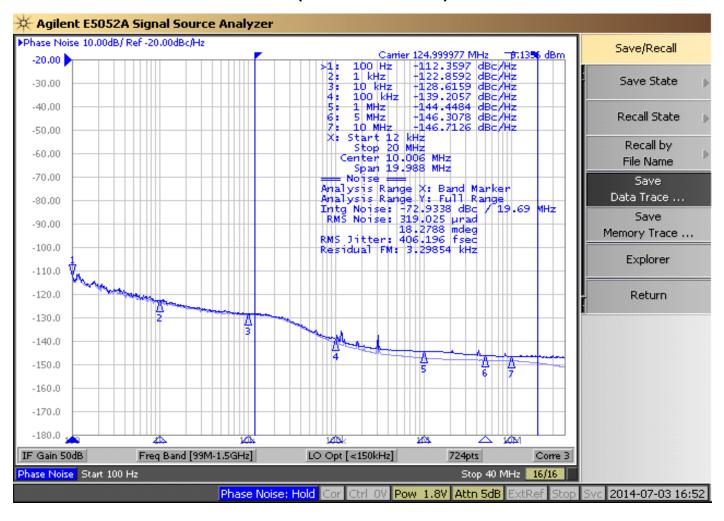
⁴ For RMS figures, additive jitter is calculated by solving the following equation: Additive jitter = SQRT[(total jitter)^2 - (input jitter)^2]

⁵ Driven by 9FGV0831 or equivalent

⁶ Driven by Rohde&Schwarz SMA100



Additive Phase Jitter Plot: 125M (12kHz to 20MHz)





General SMBus Serial Interface Information

How to Write

- Controller (host) sends a start bit
- Controller (host) sends the write address
- IDT clock will acknowledge
- Controller (host) sends the beginning byte location = N
- IDT clock will acknowledge
- Controller (host) sends the byte count = X
- IDT clock will acknowledge
- Controller (host) starts sending Byte N through Byte N+X-1
- IDT clock will acknowledge each byte one at a time
- Controller (host) sends a Stop bit

	Index Blo	ock \	Write Operation
Controll	er (Host)		IDT (Slave/Receiver)
Т	starT bit		
Slave A	Address		
WR	WRite		
			ACK
Beginning	g Byte = N		
			ACK
Data Byte	Count = X		
			ACK
Beginnin	g Byte N	×	
		X Byte	ACK
0] ,	
0			0
0			0
			0
Byte N	+ X - 1		
			ACK
Р	stoP bit		

Note: SMBus address is latched on SADR pin.

How to Read

- Controller (host) will send a start bit
- Controller (host) sends the write address
- IDT clock will acknowledge
- Controller (host) sends the beginning byte location = N
- IDT clock will acknowledge
- Controller (host) will send a separate start bit
- Controller (host) sends the read address
- IDT clock will acknowledge
- IDT clock will send the data byte count = X
- IDT clock sends Byte N+X-1
- IDT clock sends Byte 0 through Byte X (if X_(H) was written to Byte 8)
- Controller (host) will need to acknowledge each byte
- Controller (host) will send a not acknowledge bit
- Controller (host) will send a stop bit

	Index Block Read Operation						
Co	ntroller (Host)		IDT (Slave/Receiver)				
Т	starT bit						
S	lave Address						
WR	WRite						
			ACK				
Beg	inning Byte = N						
			ACK				
RT	Repeat starT						
S	lave Address						
RD	ReaD						
			ACK				
			Data Byte Count=X				
	ACK						
			Beginning Byte N				
	ACK						
		வ	0				
	0	X Byte	0				
	0	×	0				
	0						
			Byte N + X - 1				
N	Not acknowledge						
Р	stoP bit						



SMBus Table: Output Enable Register ¹

Byte 0	Name	Control Function	Туре	0	1	Default
Bit 7	Reserved					
Bit 6	DIF OE3	Output Enable	RW	Low/Low	Enabled	1
Bit 5	DIF OE2	Output Enable	RW	Low/Low	Enabled	1
Bit 4	Reserved					
Bit 3	DIF OE1	Output Enable	RW	Low/Low	Enabled	1
Bit 2		Reserved				1
Bit 1	DIF OE0	Output Enable	RW	Low/Low	Enabled	1
Bit 0		Reserved				1

^{1.} A low on these bits will overide the OE# pin and force the differential output Low/Low

SMBus Table: PLL Operating Mode and Output Amplitude Control Register

Byte 1	Name	Control Function	Туре	0	1	Default
Bit 7	PLLMODERB1	PLL Mode Readback Bit 1	R	See PLL Operating Mode Table		Latch
Bit 6	PLLMODERB0	PLL Mode Readback Bit 0	R	See PLL Opera	Latch	
Bit 5	PLLMODE SWCNTRL	Enable SW control of PLL Mode	RW	Values in B1[7:6]	Values in B1[4:3]	0
DIL 3	I LEINOBE_SWENTE	Lilable 3W Control of LE Wode	IXVV	set PLL Mode	set PLL Mode	U
Bit 4	PLLMODE1	PLL Mode Control Bit 1	RW ¹	See PLL Operating Mode Table		0
Bit 3	PLLMODE0	PLL Mode Control Bit 0	RW ¹	See FLL Opera	ing wode rable	0
Bit 2		Reserved				1
Bit 1	AMPLITUDE 1	Controls Output Amplitude	RW	00 = 0.6V	01 = 0.7V	1
Bit 0	AMPLITUDE 0	Controls Output Amplitude	RW	10= 0.8V	11 = 0.9V	0

^{1.} B1[5] must be set to a 1 for these bits to have any effect on the part.

SMBus Table: DIF Slew Rate Control Register

Byte 2	Name	Control Function	Туре	0	1	Default
Bit 7	Reserved					
Bit 6	SLEWRATESEL DIF3	Slew Rate Selection	RW	2 V/ns	3 V/ns	1
Bit 5	SLEWRATESEL DIF2	Slew Rate Selection	RW	2 V/ns	3 V/ns	1
Bit 4	Reserved					
Bit 3	SLEWRATESEL DIF1	Slew Rate Selection	RW	2 V/ns	3 V/ns	1
Bit 2		Reserved				1
Bit 1	SLEWRATESEL DIF0	Slew Rate Selection	RW	2 V/ns	3 V/ns	1
Bit 0	Reserved					1

SMBus Table: Frequency Select Control Register

Byte 3	Name	Control Function	Туре	0	1	Default
Bit 7		Reserved				1
Bit 6	Reserved					
Bit 5	FREQ_SEL_EN	Enable SW selection of frequency	RW	SW frequency change disabled	SW frequency change enabled	0
Bit 4	FSEL1	Freq. Select Bit 1	RW ¹	See Frequency	0	
Bit 3	FSEL0	Freq. Select Bit 0	RW ¹	Oce i requerie	y delect fable	0
Bit 2		Reserved				1
Bit 1	Reserved					1
Bit 0	SLEWRATESEL FB	Adjust Slew Rate of FB	RW	2 V/ns	3 V/ns	1

11

Byte 4 is Reserved and reads back 'hFF

^{1.} B3[5] must be set to a 1 for these bits to have any effect on the part.



SMBus Table: Revision and Vendor ID Register

Byte 5	Name	Control Function	Туре	0	1	Default
Bit 7	RID3		R		0	
Bit 6	RID2	Revision ID	R	A rev = 0000		0
Bit 5	RID1	Revision ID	R			0
Bit 4	RID0		R		0	
Bit 3	VID3		R			0
Bit 2	VID2	VENDOR ID	R	0001	- IDT	0
Bit 1	VID1	VENDOR ID	R	0001 = IDT		0
Bit 0	VID0	1	R			1

SMBus Table: Device Type/Device ID

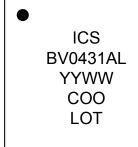
Byte 6	Name	Control Function	Туре	0	1	Default
Bit 7	Device Type1	Device Type	R	00 = FGV, 01 = DBV,		0
Bit 6	Device Type0	Device Type	R	10 = DMV, 1	1= Reserved	1
Bit 5	Device ID5		R			0
Bit 4	Device ID4		R			0
Bit 3	Device ID3	Device ID	R	000100 bina	ny or 04 hey	0
Bit 2	Device ID2	Device ib	R	000100 billa	ly or o 4 nex	1
Bit 1	Device ID1		R			0
Bit 0	Device ID0		R			0

SMBus Table: Byte Count Register

Byte 7	Name	Control Function	Туре	0	1	Default
Bit 7		Reserved				0
Bit 6	Reserved					
Bit 5	Reserved					
Bit 4	BC4		RW			0
Bit 3	BC3		RW	Writing to this regist	er will configure how	1
Bit 2	BC2	Byte Count Programming	RW	many bytes will be r	ead back, default is	0
Bit 1	BC1		RW	= 8 b	ytes.	0
Bit 0	BC0		RW			0



Marking Diagrams





Notes:

- 1. "LOT" is the lot sequence number.
- 2. "COO" denotes country of origin.
- 3. YYWW is the last two digits of the year and week that the part was assembled.
- 4. Line 2: truncated part number
- 5. "L" denotes RoHS compliant package.
- 6. "I" denotes industrial temperature range device.

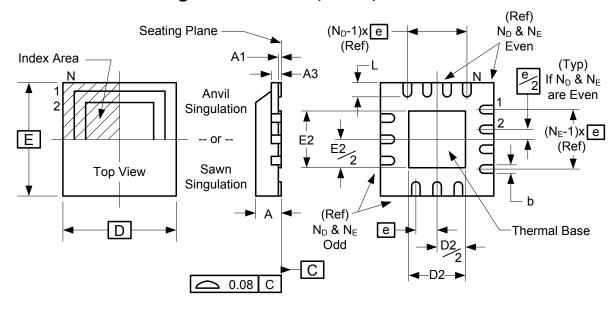
Thermal Characteristics

PARAMETER	SYMBOL	CONDITIONS	PKG	TYP VALUE	UNITS	NOTES
Thermal Resistance	θ_{JC}	Junction to Case	NLG32 42 2.4 39 33 28 27	42	°C/W	1
	θ_{Jb}	Junction to Base		2.4	°C/W	1
	θ_{JA0}	Junction to Air, still air		39	°C/W	1
	θ_{JA1}	Junction to Air, 1 m/s air flow		33	°C/W	1
	θ_{JA3}	Junction to Air, 3 m/s air flow		28	°C/W	1
	θ_{JA5}	Junction to Air, 5 m/s air flow		°C/W	1	

¹ePad soldered to board



Package Outline and Package Dimensions (NLG32)



	Millimeters		
Symbol	Min	Max	
Α	0.80	1.00	
A1	0	0.05	
A3	0.20 Reference		
b	0.18	0.3	
е	0.50 BASIC		
D x E BASIC	5.00 x 5.00		
D2 MIN./MAX.	3.00	3.30	
E2 MIN./MAX.	3.00	3.30	
L MIN./MAX.	0.30	0.50	
N	32		
N_D	8	8	
N _E	8	3	

Ordering Information

Part/Order Number	Shipping Packaging	Package	Temperature	
9DBV0431AKLF	Trays	32-pin VFQFPN	0 to +70° C	
9DBV0431AKLFT	Tape and Reel	32-pin VFQFPN	0 to +70° C	
9DBV0431AKILF	Trays	32-pin VFQFPN	-40 to +85° C	
9DBV0431AKILFT	Tape and Reel	32-pin VFQFPN	-40 to +85° C	

[&]quot;LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

[&]quot;A" is the device revision designator (will not correlate with the datasheet revision).



Revision History

Rev.	Initiator	Issue Date	Description	Page #
A	RDW	8/13/2012	 Removed "Differential" from DS title and Recommended Application, corrected typo's in Description. Corrected spelling error in pullup/pulldown text under pinout Updated all electrical tables and added "Industry Limit" column to "Phase Jitter Parameters". Updated Byte3[0] to be consistent with Byte 2. Updated Byte6[7:6] definition. Added thermal data to page 12. Added NLG32 to "Package Outline and Package Dimensions" on page 13. Move to final 	1,2,5- 8,10, 12,13
В	RDW	2/28/2013	1. "Input/Supply/Common Parameters" table modified as follows: a. Updated Single-ended input logic thresholds to include missing mid-level on tri-level inputs. Adjusted logic thresholds as follows: i. Changed VIH min. from 0.65*VDD to 0.75*VDD ii. Changed VIL max. from 0.35*VDD to 0.25*VDD iii. Added missing mid-level input voltage spec (VIM) of 0.4*VDD to 0.6*VDD. iv. Clarified conditions for these specifications, accordingly. b. Clarified the operating conditions and voltages of the SMBus to make it clear that the SMBus operates at <3.3V by addition of footnotes 4 and 5 to "Input/Supply/Common Parameters" table. 2. Slight modifications of Slew Rates and typical values in the "DIF 0.7V Low Power Differential Outputs" table. 3. "Current Consumption" table modifed as follows: a. Overall current consumption values lowered b. VDDA is now grouped with VDD1.8 instead of VDDR c. Added separate current specs for PLL bypass mode. d. Clarified that CKPWRDG_PD# is low for power down current. 4. "Output Duty Cycle, Jitter, Skew and PLL Characterisitics" table modifed as follows: a. Bypass mode Input-to-Output skew changed from 3000 to 4500ps to 2550 to 4200ps. Typical value reduced from 3500ps to 3370ps. b. Separate Output-to-Output skew spec added for Industrial temp. c. Additive cycle-to-cycle jitter spec reduced to 1ps max. 5. "Phase Jitter Parameters" modifed as follows: a. Corrected typo in PLL Mode conditions for tjPHSGMII. Frequency integration range is 1.5MHz to 10MHz. Bypass mode conditions were correct.	5-8
С	RDW	11/26/2014	1. Updated front page text for consistency and updated block diagram resistor colors to highlight internal resistors. 2. Updated max frequency of 100MHz PLL mode from 110MHz to 140MHz 3. Updated max frequency of 125MHz PLL mode from 137.5MHz to 175MHz 4. Updated max frequency of 50MHz PLL mode from 55MHz to 65MHz 5. Updated Key Specifications with additive phase jitter. 6. Added additive phase jitter plot to specifications.	Various
D	RDW	4/3/2015	Updated block diagram with new format showing individual outputs instead of bussed outputs. Updated pin out and pin descriptions to show ePad on package connected to ground.	1-4
Е	RDW	4/22/2016	Updated max frequency of 100MHz PLL mode to 140MHz Updated max frequency of 125MHz PLL mode to 175MHz Updated max frequency of 50MHz PLL mode to 65MHz	6



Corporate Headquarters 6024 Silver Creek Valley Road San Jose, CA 95138 USA Sales

1-800-345-7015 or 408-284-8200

Fax: 408-284-2775 www.idt.com/go/sales **Tech Support**

www.idt.com/go/support

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